

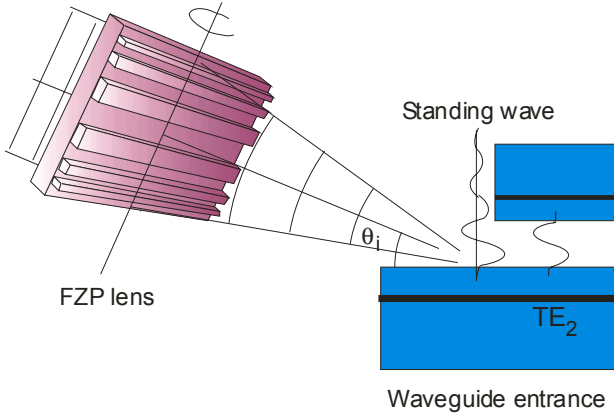
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2) ESRF.

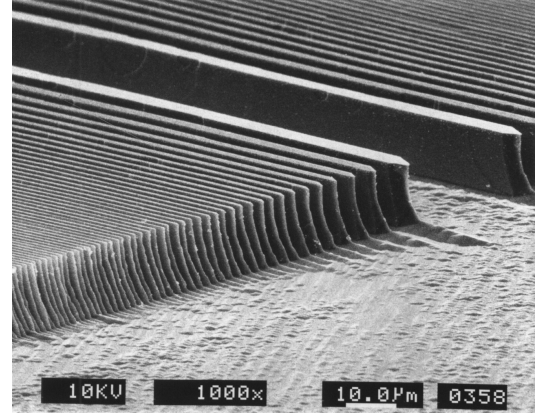
In Fig. 4, the numerically calculated and the measured far field intensity distributions  $I(\theta_i, \theta_e)$  are shown as a function of incidence angle  $\theta_i$  and exit angle  $\theta_e$ . The waveguide gap width is 957 nm. The different waveguide modes show up as maxima along the diagonal. The horizontal width of the diagonal corresponds

to the angular distribution expected from the lens height and focal length. Also, along the diagonal a weak beating period can be seen, which is indicative of multimode interference. This reduced visibility is an indication that the beam is partially coherence. The vertical transverse coherence length in our situation was 80 microns at the position of the lens, which itself is 200 micron high. At large waveguide widths, the intensity in the waveguide is not fully coherent, while at gaps much smaller than 350 nm (the outermost zone width), the intensity is fully coherent in the vertical direction.

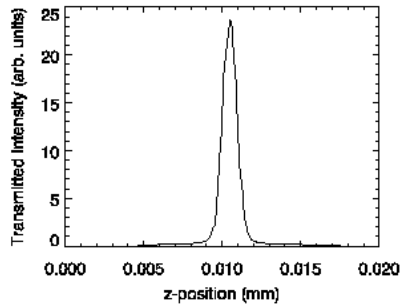
The results of this experiment show that it is possible to enhance the flux inside a planar waveguide by a factor 54, and at gap settings below the outermost zone width, the intensity is still fully coherent. This enables a large range of coherent scattering experiments to be performed in small scattering volumes at greatly enhanced flux.



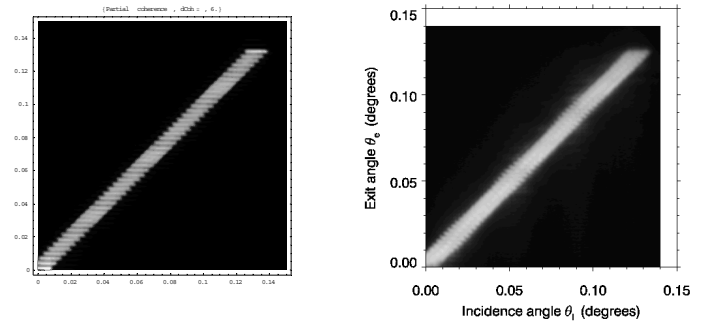
**Fig. 1** Schematic of the experimental setup. The FZP-lens focuses a 200 micron incident beam into a ca. 1 micron size spot at the entrance of the waveguide, where the waveguide modes are excited. By rotating the lens around its axis, the phase shift between the trenches and ridges can be tuned to the desired the photon energy. The focal length of the lens is 74 cm at 13.3 keV.



**Fig. 2** Electron micrograph of a one-dimensional zone plate lens, which is used to focus the beam. The lens consists of a rectangular pattern of trenches and ridges on a 5  $\mu\text{m}$  thick silicon membrane. The outermost zone width is 350 nm. The height of the ridges is 5.5  $\mu\text{m}$ . The lens size perpendicular to the stripes is 200  $\mu\text{m}$  and along the stripes 2.5 mm.



**Fig. 3** Total transmitted intensity through the waveguide as a function of the vertical lens position  $z$  for a waveguide gap  $W=300$  nm. The profile represents the image of the undulator source, convoluted with the gap width of the waveguide and the diffraction limited resolution of the FZP lens.



**Fig. 4** The intensity distribution in the far field  $I(\theta_i, \theta_e)$  as a function of incidence angle  $\theta_i$  and exit angle  $\theta_e$  for a 957 nm waveguide gap with a prefocused beam. To the left is shown a numerical calculation for a partially coherent beam, as expected from the beam properties. To the right are shown the experimental data. The broadened diagonal is caused by the angular distribution in the converging focused waves.

## References

- [1] M.J. Zwanenburg, H.G. Ficke, H. Neerings, and J.F. van der Veen, Rev. Sci. Instrum. 71 (4) pp. 1723-1732 (2000).
- [2] M.J. Zwanenburg, J.F. Peters, J.H.H. Bongaerts, S.A. de Vries, D. L. Abernathy, and J. F. van der Veen, Phys. Rev. Lett. 82 pp. 1696 (1999).
- [3] C. David, B. Noehammer, and E. Ziegler, submitted to Applied Phys. Letters.